



US009411013B2

(12) **United States Patent**
Richards et al.

(10) **Patent No.:** **US 9,411,013 B2**
(45) **Date of Patent:** **Aug. 9, 2016**

(54) **INSTRUMENT FOR AUTOMATED TESTING OF DISPLAYS**

(71) Applicant: **Google Inc.**, Mountain View, CA (US)

(72) Inventors: **Evan M. Richards**, Santa Clara, CA (US); **Anurag Gupta**, San Jose, CA (US)

(73) Assignee: **Google, Inc.**, Mountain View, CA (US)

(*) Notice: Subject to any disclaimer, the term of this patent is extended or adjusted under 35 U.S.C. 154(b) by 203 days.

(21) Appl. No.: **14/181,086**

(22) Filed: **Feb. 14, 2014**

(65) **Prior Publication Data**

US 2015/0234006 A1 Aug. 20, 2015

(51) **Int. Cl.**

G01N 21/88 (2006.01)

G01R 31/308 (2006.01)

G02F 1/13 (2006.01)

G01N 21/95 (2006.01)

(52) **U.S. Cl.**

CPC **G01R 31/308** (2013.01); **G02F 1/1309** (2013.01); **G01N 2021/9513** (2013.01)

(58) **Field of Classification Search**

CPC **G02F 1/1309**
See application file for complete search history.

(56) **References Cited**

U.S. PATENT DOCUMENTS

7,826,057 B2 11/2010 Kim et al.
7,831,086 B2* 11/2010 Kondo G06T 3/0062
345/419

7,941,237 B2 5/2011 Parker et al.
8,492,739 B2 7/2013 Choi et al.
8,561,288 B2 10/2013 Bawolek
2003/0215129 A1* 11/2003 Yang G06T 7/0002
382/149
2005/0167620 A1* 8/2005 Cho G01N 21/95
250/559.45
2008/0284455 A1* 11/2008 Obikane G01R 31/2893
324/754.08
2010/0148083 A1* 6/2010 Brown G01J 3/02
250/372
2013/0068368 A1 3/2013 Kim et al.
2014/0009181 A1* 1/2014 Xue G01R 31/312
324/754.03
2014/0295771 A1* 10/2014 Finlow-Bates H04W 24/06
455/67.14

* cited by examiner

Primary Examiner — Tung X Nguyen

Assistant Examiner — Feba Pothen

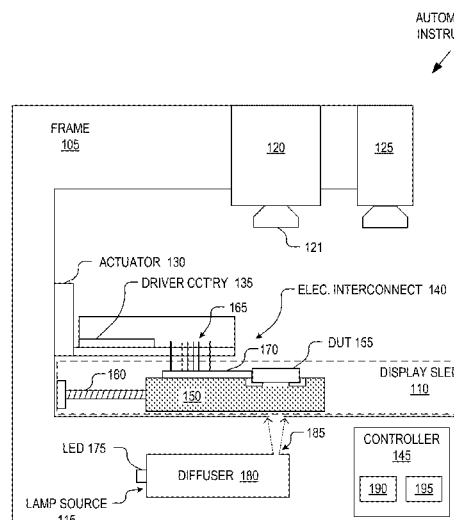
(74) *Attorney, Agent, or Firm* — Blakely Sokoloff Taylor & Zafman LLP

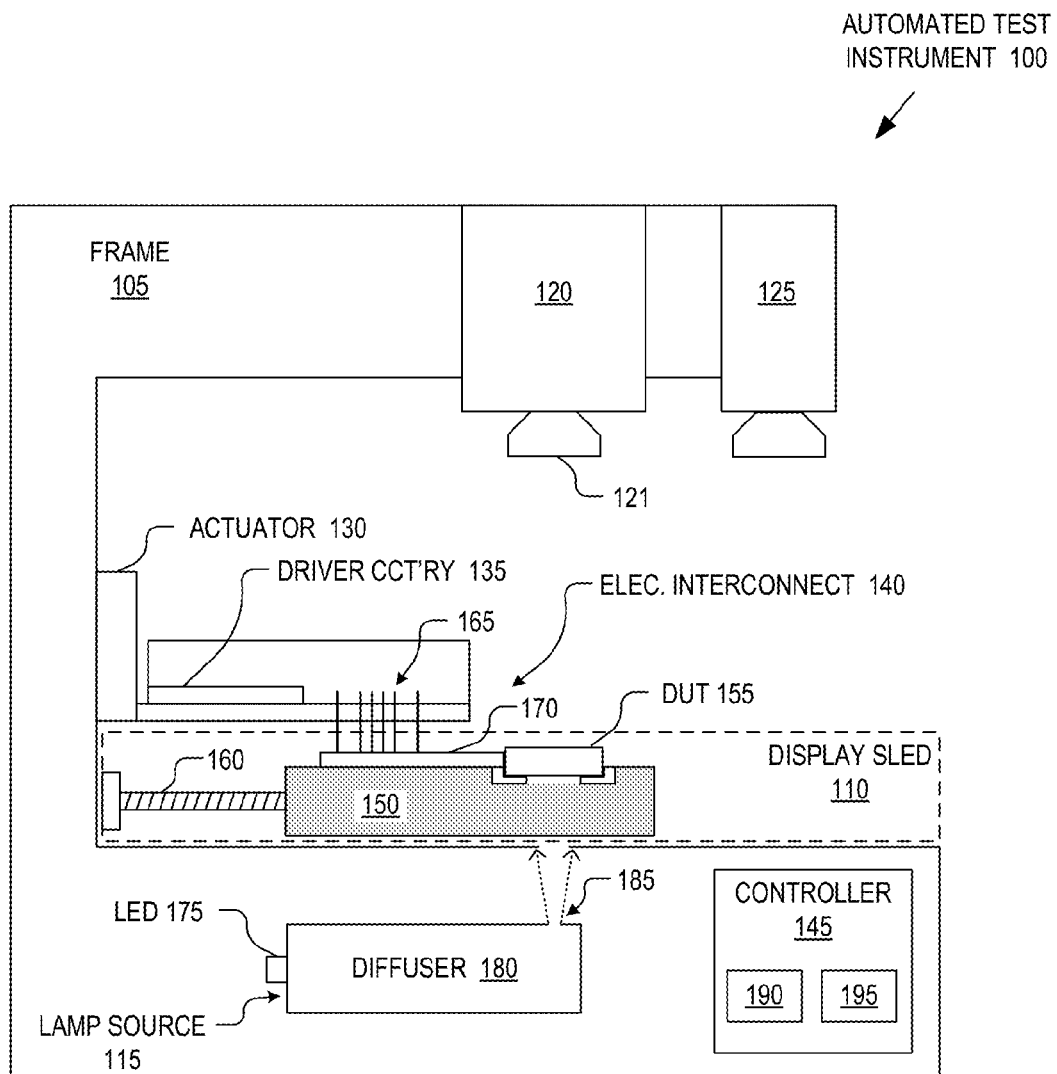
(57)

ABSTRACT

A test apparatus includes a display sled having a mount for holding a display under test (“DUT”). The display sled is supported by a frame and moves between a test position and a load position. A lamp source is supported by the frame and positioned to illuminate the DUT when the display sled is in the test position. A measurement camera is supported by the frame and positioned to capture one or more test images output by the DUT when the DUT is illuminated by the lamp source. Driver circuitry generates the one or more test images to drive the DUT. An electrical interconnect establishes an electrical connection between the driver circuitry and the DUT when the display sled is in the test position. An actuator is coupled to physically manipulate the electrical interconnect to engage or disengage the electrical connection between the driver circuitry and the DUT.

20 Claims, 5 Drawing Sheets





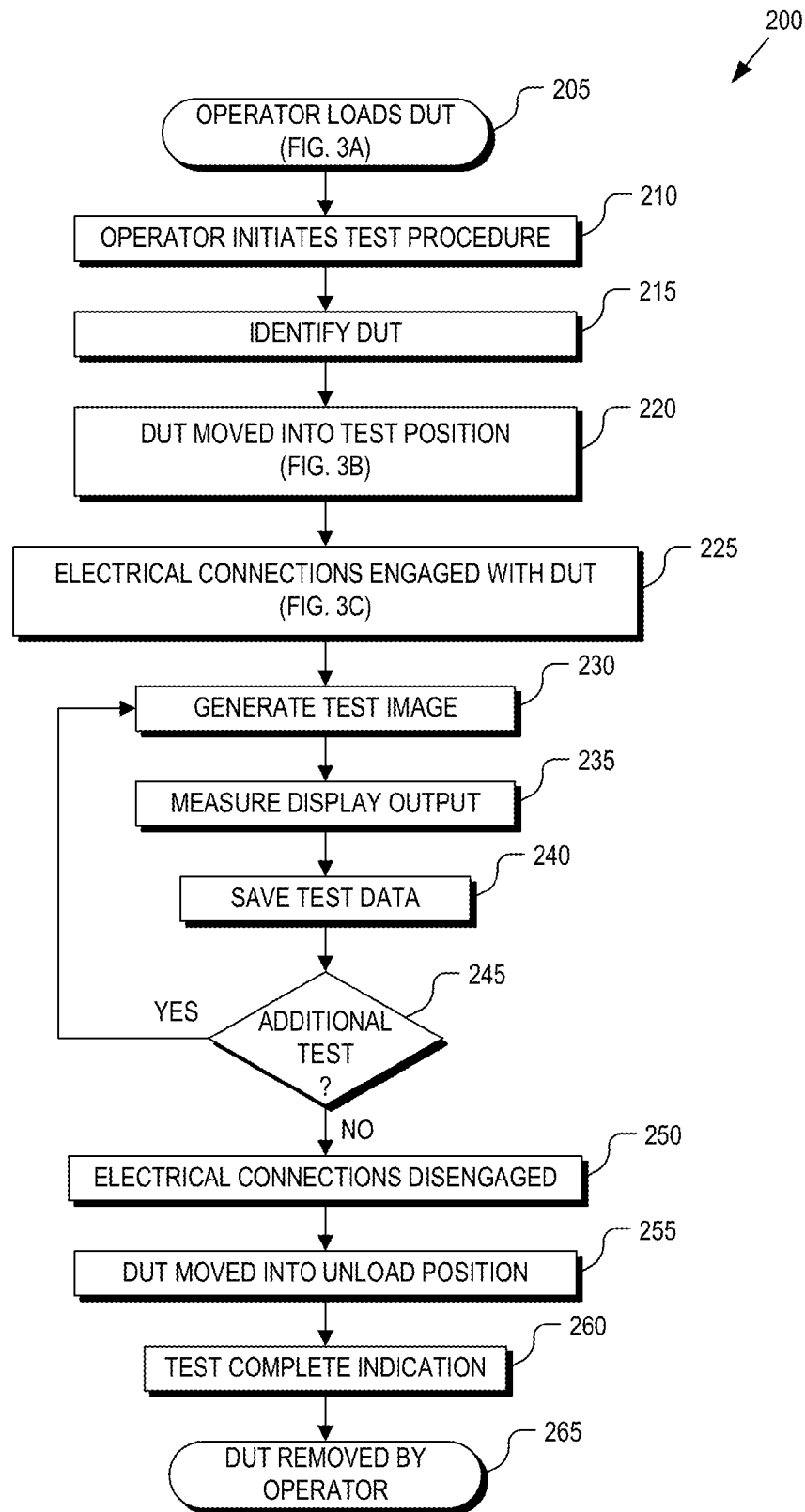
**FIG. 2**

FIG. 3A

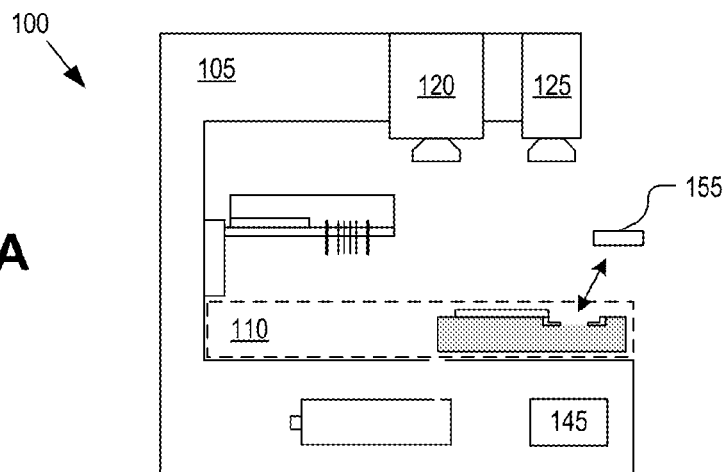


FIG. 3B

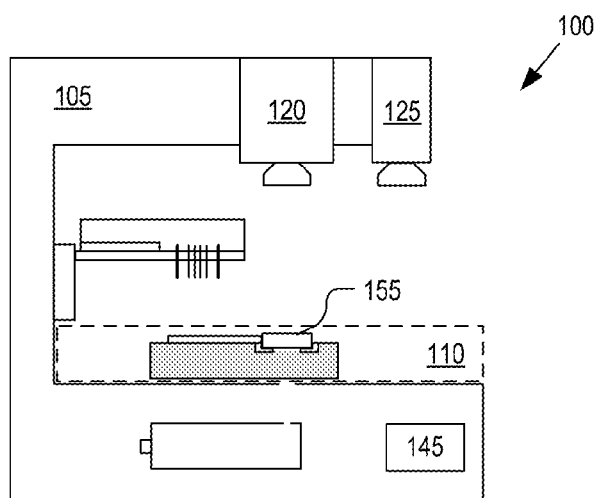
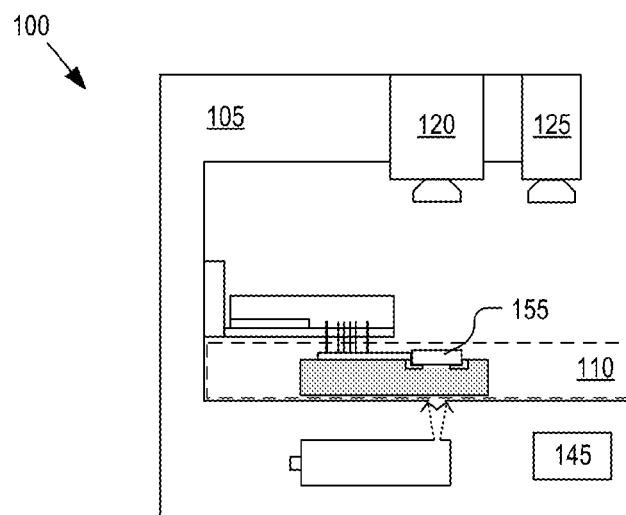
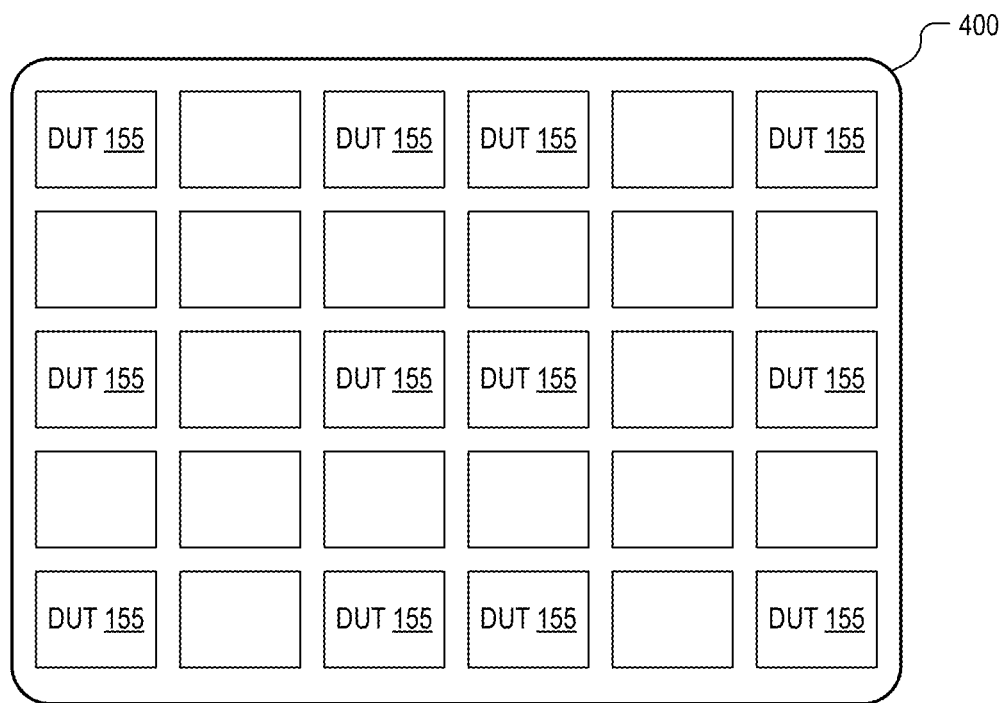


FIG. 3C



**FIG. 4**

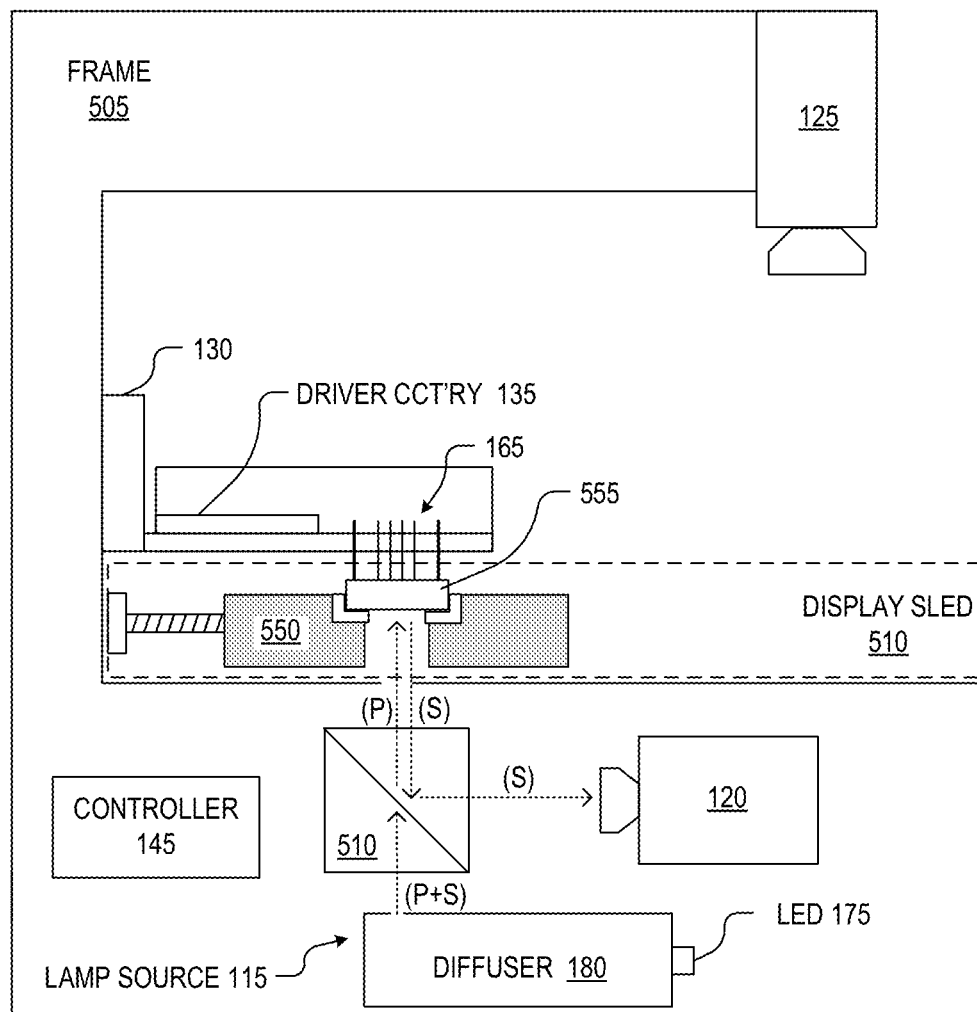


FIG. 5

INSTRUMENT FOR AUTOMATED TESTING OF DISPLAYS

TECHNICAL FIELD

This disclosure relates generally to instruments for testing displays.

BACKGROUND INFORMATION

A liquid crystal displays (“LCD”) is a well-known display technology. Unpolarized or linearly polarized light is incident on the LCD. A first polarizer polarizes the light. Liquid crystals inside the display rotate the polarization state of the light based on the voltage applied. A final output polarizer only transmits one polarization direction. Thus, the amount of polarization rotation modulates the brightness of the light to create the desired image. This is done using Malus’ Law where $I = I_0 \cos^2(\theta)$. I_0 is the incident power, θ is the angle between the rotated light and the output polarizer, and I is the output power. Measuring the resulting image that goes to the observer is challenging in a test environment. The manufacturers of these parts use human operators with optical projectors to enlarge and assess the image performance from the LCD for these small display panels.

Liquid crystal on silicon (“LCOS”) is a display technology that uses polarized light to create an image. As an example, when p-polarized light is used to illuminate an LCOS display, the LCOS changes the incident p-polarization into a reflected mix of p-polarization and s-polarization based on the desired pixel intensity. The s-polarized portion is transmitted to the user using a polarizing beam splitter (“PBS”) while the p-polarized portion is thrown away. Again, measuring the resulting image that goes to the observer is challenging in a test environment. The manufacturers of these parts also use human operators with optical projectors to enlarge and assess the image performance from the LCOS.

BRIEF DESCRIPTION OF THE DRAWINGS

Non-limiting and non-exhaustive embodiments of the invention are described with reference to the following figures, wherein like reference numerals refer to like parts throughout the various views unless otherwise specified. The drawings are not necessarily to scale, emphasis instead being placed upon illustrating the principles being described.

FIG. 1 is a block diagram illustrating an automated test instrument for testing the performance of emissive or transmissive displays, in accordance with an embodiment of the disclosure.

FIG. 2 is a flow chart illustrating operation of an automated test instrument for testing the performance of displays, in accordance with an embodiment of the disclosure.

FIG. 3A illustrates loading/unloading a display into the automated test instrument, in accordance with an embodiment of the disclosure.

FIG. 3B illustrates a display that has been moved into a test position of the automated test instrument, in accordance with an embodiment of the disclosure.

FIG. 3C illustrates how electrical connections to the display loaded into the automated test instrument are achieved, in accordance with an embodiment of the disclosure.

FIG. 4 illustrates a tray for holding multiple displays for successive testing in an automated test instrument, in accordance with an embodiment of the disclosure.

FIG. 5 is a block diagram illustrating an automated test instrument for testing the performance of a reflective display,

such as a liquid crystal on silicon (“LCoS”) display, in accordance with an embodiment of the disclosure.

DETAILED DESCRIPTION

Embodiments of a system, apparatus, and method of operation for automated measuring/testing of displays, such as microdisplays, are described herein. In the following description numerous specific details are set forth to provide a thorough understanding of the embodiments. One skilled in the relevant art will recognize, however, that the techniques described herein can be practiced without one or more of the specific details, or with other methods, components, materials, etc. In other instances, well-known structures, materials, or operations are not shown or described in detail to avoid obscuring certain aspects.

Reference throughout this specification to “one embodiment” or “an embodiment” means that a particular feature, structure, or characteristic described in connection with the embodiment is included in at least one embodiment of the present invention. Thus, the appearances of the phrases “in one embodiment” or “in an embodiment” in various places throughout this specification are not necessarily all referring to the same embodiment. Furthermore, the particular features, structures, or characteristics may be combined in any suitable manner in one or more embodiments.

FIG. 1 is a block diagram illustrating an automated test instrument **100** for testing the performance of emissive or transmissive displays, in accordance with an embodiment of the disclosure. The illustrated embodiment of automated test instrument **100** includes a frame **105**, a display sled **110**, a lamp source **115**, a measurement camera **120**, an identification camera **125**, an actuator **130**, driver circuitry **135**, an electrical interconnect **140**, and a controller **145**. The illustrated embodiment of display sled **110** includes a mount **150** for holding the display under test (“DUT”) **155** and a sled actuator **160**. The illustrated embodiment of electrical interconnect **140** includes terminals **165** and contact region **170**. The illustrated embodiment of lamp source **115** includes a light emitting diode (“LED”) **175** and diffuser **180** having an emission aperture **185**. The illustrated embodiment of controller **145** includes logic **190** and memory **195**.

Automated test instrument **100** is an apparatus for measuring and testing displays for faults. Such displays include microdisplays, such as transmissive displays (e.g., backlit LCD displays) or emissive displays (e.g., organic light emitting diode (“OLED”) displays). Automated test instrument **100** eliminates subjective human judgment in the measurement process and provides rapid automated testing of one or more displays under test (“DUTs”) **155**. Automated test instrument **500**, illustrated in FIG. 5, is similar to automated test instrument **100**, as is discussed below, but is designed for testing reflective displays, such as a liquid crystal on silicon (“LCoS”) display. Automated test instrument **500** is discussed in greater detail below in connection with FIG. 5.

Automated test instrument **100** is capable of performing multiple different types of test procedures on a given DUT **155**. For example, DUT **155** may be driven with a reference test pattern or test image, the test image output by DUT **155** captured by measurement camera **120**, and the captured test image analyzed by logic **190** of controller **145** to determine if DUT **155** has a failure. Determining whether DUT **155** has a failure may include comparing the capture test image against various threshold values, such as number of acceptable faulty pixels (e.g., 0, 1, 2, etc.), contrast levels, black levels, response time, color quality, etc. Any number of image analysis algorithms may be applied. In one embodiment, measure-

ment camera **120** has sufficient resolution to identify a single faulty pixel on DUT **155**. The test results may then be logged against an identifier for the given DUT **155** and stored into memory **195** for subsequent output. In one embodiment, test results include an itemization of failures on a per-pixel basis.

Automated test instrument **100** includes display sled **110**, which moves between an load/unload position (e.g., see FIG. 3A) and a test position (e.g., see FIGS. 1 and 3B). This provides the operator easy access for loading the instrument with DUT **155** and is functional to accept different types of displays having different electrical interfaces. Display sled **110** includes mount **150**, which is amenable to accepting and holding displays of different shapes and sizes. Display sled **110**, along with mount **150**, may translate or rotate between the load/unload position and the test position on a track, guide, hinge, or otherwise. In the illustrated embodiment, display sled **110** is translated between the two positions under the influence of sled actuator **160**. Sled actuator **160** may be implemented using a variety of different actuating technologies including a screw drive, a belt system, an electro-magnetic actuator, a servo, or otherwise. In other embodiments, display sled **110** may be physically manipulated between the load/unload position and the test position by the operator.

Once in the test position, DUT **155** may be driven with one or more test images by driver circuitry **135**. Driver circuitry **135** may include a video chip or rendering circuitry to generate the test images and provide operational power and control signals to DUT **155**. Electrical connections are established between driver circuitry **135** and DUT **155** via electrical interconnect **140** in concert with actuator **130**. Electrical interconnect **140** includes terminals **165** that make physical and electrical contact with contacts on contact region **170** disposed on display sled **110**. Actuator **130** physically manipulates terminals **165** to engage contact region **170** once display sled **110** is moved to the test position. In the illustrated embodiment, terminals **165** are translated along a first axis that is orthogonal to a second axis along which display sled **110** is translated.

Actuator **130** may be implemented using a variety of actuating technologies including servos, electro-mechanical motors, electro-static actuator, micro-electro-mechanical actuators, or otherwise. In one embodiment, terminals **165** may be implemented using pogo pins that align with contact pads coupled to a flex ribbon used to implement contact region **170**. Of course, other physical interconnect elements and geometries may be implemented. Similarly, other orientations and configurations for actuating electrical interconnect **140** to engage/disengage an electrical connection with DUT **155** may be implemented as well.

In the illustrated embodiment, lamp source **115** is disposed below display sled **110** to illuminate DUT **155** from its backside such that DUT **155** outputs a test image to measurement camera **120** disposed above display sled **110**. Lamp source **115** may be implemented using a variety of lamp technologies including LEDs, fluorescent lights, halogen lights, or otherwise. Lamp source **115** may be a monochromatic light source, a multi-color light source, a broadband light source, or otherwise. In the illustrated embodiment, lamp source **115** includes an LED **175** that launches lamp light into a diffuser **180**. Diffuser **180** includes a cavity with diffuse inner sides walls that homogenize the lamp light and emit the lamp light through an emission aperture **185** aligned with DUT **155**. In one embodiment, lamp source **115** further includes a polarizer for generating polarized light.

In the illustrated embodiment, measurement camera **120** is disposed above DUT **155** to capture the test image output from DUT **155** when display sled **110** is in the test position.

Measurement camera **120** may be implemented using various camera technologies (e.g., CMOS or CCD cameras), and in at least some embodiments, have a resolution sufficient to identify a single faulty pixel or multiple pixel failures on a per pixel basis.

In the illustrated embodiment, camera module **120** includes a lens assembly **121** for focusing on DUT **155**. Lens assembly **121** may be implemented as a telecentric lens while measurement camera **120** may be provided with an offset adjustment (e.g., vertical adjustment). A telecentric lens maintains a constant magnification despite various offsets between lens assembly **121** and DUT **155**. This accommodates different DUT **155** form factors having the same display size. The vertical offset adjustment facilities bring the captured test image into focus for different DUT **155** form factors. Alternatively, lens assembly **121** may be implemented with a variable focus lens (e.g., autofocus lens) and used in connection with feature detection and size correlation logic within controller **145** or measurement camera **120**. Again, the variable focus lens facilitates different size and form factors for DUT **155**.

Code camera **125** is provided in automated test instrument **100** to enable an auto identification feature. Code camera **125** may be implemented with a conventional CCD or CMOS image sensor, a barcode scanner, or otherwise. Code camera **125** operates to read identifying marks on DUT **155** (e.g., a bar code, product code, serial number, etc.). This information may be used to identify the particular type of DUT **155**, select appropriate test procedures from a catalog of test procedures (e.g., test images), and index the test results with an identifier for output or storing to memory **195**.

Controller **145** is coupled to the various operational components of automated test instrument **100** to control and synchronize their operation in an automated manner. Controller **145** includes logic **190** that controls the operational phases of display sled **110**, lamp source **115**, actuator **130**, driver circuitry **135**, measurement camera **120**, and code camera **125**. Logic **190** may be implemented as hardware logic (e.g., application specific integrated circuit, field programmable gate array, or otherwise), software logic/instructions executed on a micro-processor, or a combination of both. Memory **195** may include volatile and/non-volatile memory. Although not illustrated, controller **145** may further include various input/output ports and interfaces for receiving user inputs and outputting user prompts and test results.

FIG. 2 is a flow chart illustrating a process **200** of operating automated test instrument **100** for testing the performance of DUT **155**, in accordance with an embodiment of the disclosure. Process **200** is described with reference to FIGS. 1, 3A, 3B, and 3C. The order in which some or all of the process blocks appear in process **200** should not be deemed limiting. Rather, one of ordinary skill in the art having the benefit of the present disclosure will understand that some of the process blocks may be executed in a variety of orders not illustrated, or even in parallel.

In a process block **205**, an operator loads DUT **155** into mount **150** of display sled **110** (see FIG. 3A). When inserting DUT **155** into automated test instrument **100**, display sled **110** is moved to the load/unload position, as illustrated in FIG. 3A. Mount **150** may include a friction fit, adjustable clamps, or otherwise that hold DUT **155** temporarily and securely in place. Once loaded, the operator initiates a test procedure with a user input selection (process block **210**). In one embodiment, the user input may be solicited and received from a user interface (e.g., button, externally coupled computer, etc.) communicatively coupled to controller **145**.

5

Once a test procedure has been initiated, automated test instrument **100** identifies the specific DUT **155** loaded into display sled **110** using code camera **125**. In a process block **215**, display sled **110** moves DUT **155** into optical aligned with code camera **125** where code camera **125** reads an identifying code physically printed on DUT **155**. The identifying code may be a barcode, a serial number, a product number, or various other marks. In various embodiments, code camera **125** may acquire an image of a mark on DUT **155** or an image of DUT **155** itself, and character recognition or image recognition techniques used to identify the type of display that is DUT **155**. For example, controller **145** may use the identifying marks to determine the particular model of display as well as whether the display is transmissive, reflective, or emissive. If DUT **155** is determined to be transmissive or reflective, then lamp source **115** will be enabled as a source of lamp light. If DUT **155** is determined to be emissive, then external lamp light is not necessary and lamp source **115** remains disabled.

In a process block **220** (see FIG. 3B), display sled **110** moves DUT **155** into the test position where DUT **155** is optically aligned with measurement camera **120** and lamp source **115**. Once in the test position, electrical connections are established between driver circuitry **135** and DUT **155** (process block **225**; see FIG. 3C). In the illustrated embodiment, controller **145** causes actuator **130** to move terminals **165** vertically down and engage contact region **170**.

Once an electrical connection is established between driver circuitry **135** and DUT **155**, controller **145** enables driver circuitry **135**. Driver circuitry **135** both powers DUT **155** and drives DUT **155** with one or more test images (process block **230**). For example, a test image may be an all-black image to identify failed pixels in the case of a backlit LCD display, an all red, green, or blue image to identify failed pixels in the case of emissive displays, images with regular patterns, grey scale images, or otherwise. Each test image is captured by measurement camera **120** and analyzed by logic **190** of controller **145** (process block **235**). The analysis identifies a faulty pixel when a given pixel fails to satisfy a specified threshold level. Faulty pixels or other system level faults with DUT **155** are reported and saved into memory **195** as test results indexed to an identifier or part number for DUT **155** (process block **240**).

If a given DUT **155** is to be driven with multiple different test images (decision block **245**), then process **200** loops back to process block **230** and repeats until all test images have been acquired and analyzed. In a process block **250**, the electrical connection between driver circuitry **135** and DUT **155** is disengaged. In the illustrated embodiment, actuator **130** raises terminals **165** to disengage the electrical connection under the influence of controller **145**. After disengaging the electrical connections, display sled **110** moves DUT **155** to the load/unload position (process block **255**; see FIG. 3A) and automated test instrument **100** notifies the operator that the test procedure is complete (process block **260**). Finally, in a process block **265**, the operator removes DUT **155** from mount **150** of display sled **110**. In alternative embodiments (not illustrated), loading and unloading DUT **155** may also be automated.

FIG. 4 illustrates a tray **400** for holding multiple DUTs **155** for successive testing in automated test instrument **100**, in accordance with an embodiment of the disclosure. Mount **150** of display sled **110** may be modified and enlarged to support a larger tray **400** capable of holding many DUTs **155** for rapid batch testing. Although not illustrated, tray **400** may include contact regions associated with each cradle area on tray **400** for holding a separate DUT **155**. These on-tray contact

6

regions may then be engaged by terminals **165** to establish an electrical connection to a given DUT **155**. During operation, a user would load up tray **400** with a batch of DUTs **155** and automated test instrument **100** would successively execute the test procedure described in connection with FIG. 2 for each DUT **155** loaded into tray **400**. In one embodiment, display sled **110** would be capable to translation along two orthogonal axes to successively align each DUT **155** into the test position. In one embodiment, the test results are also batch reported into memory **195** for operator readout or output from the automated test instrument **100**.

FIG. 5 is a block diagram illustrating an automated test instrument **500** for testing the performance of a reflective display or reflective DUT **555**, in accordance with an embodiment of the disclosure. An example of a reflective display is a liquid crystal on silicon ("LCoS") display. Automated test instrument **500** is similar to automated test instrument **100** with at least the differences enumerated below and operates using a similar process as described in connection with FIG. 2.

The illustrated embodiment of automated test instrument **500** includes a frame **505** that supports measurement camera **120** below display sled **510**, as opposed to above. A polarizing beam splitter ("PBS") cube **510** is also included below display sled **510** and optically aligned under DUT **555** when display sled **510** is moved into the test position. During operation, lamp source **115** outputs lamp light, which can be either non-polarized light (including P & S polarizations) or polarized light (P polarized). P-polarized light passes through PBS cube **510** and illuminates DUT **555**. The operation of LCoS displays is well known. DUT **555** changes the incident p-polarization into a reflected mix of p-polarization and s-polarization based on the test image driven to the DUT **555**. PBS cube **510** reflects the s-polarization, which represents the output test image, back to measurement camera **120** where it is captured for analysis by controller **145**. Mount **550** of display sled **510** may be modified relative to mount **150** to accommodate the unique form factor of reflective displays and the fact that measurement camera **120** is disposed below display sled **510**.

It should be appreciated that it is contemplated that in various other embodiments (not illustrated) the various functional components of both automated test instruments **100** and **500** may be rearranged into other geometries and relative positions, while still achieving the same overall functions described herein.

The processes explained above are described in terms of computer software and hardware. The techniques described may constitute machine-executable instructions embodied within a tangible or non-transitory machine (e.g., computer) readable storage medium, that when executed by a machine will cause the machine to perform the operations described. Additionally, the processes may be embodied within hardware, such as an application specific integrated circuit ("ASIC") or otherwise.

A tangible machine-readable storage medium includes any mechanism that provides (i.e., stores) information in a non-transitory form accessible by a machine (e.g., a computer, network device, personal digital assistant, manufacturing tool, any device with a set of one or more processors, etc.). For example, a machine-readable storage medium includes recordable/non-recordable media (e.g., read only memory (ROM), random access memory (RAM), magnetic disk storage media, optical storage media, flash memory devices, etc.).

The above description of illustrated embodiments of the invention, including what is described in the Abstract, is not

intended to be exhaustive or to limit the invention to the precise forms disclosed. While specific embodiments of, and examples for, the invention are described herein for illustrative purposes, various modifications are possible within the scope of the invention, as those skilled in the relevant art will recognize.

These modifications can be made to the invention in light of the above detailed description. The terms used in the following claims should not be construed to limit the invention to the specific embodiments disclosed in the specification. Rather, the scope of the invention is to be determined entirely by the following claims, which are to be construed in accordance with established doctrines of claim interpretation.

What is claimed is:

1. An apparatus for testing displays, comprising:

a frame;

a display sled including a mount for holding a display under test ("DUT"), wherein the display sled is supported by the frame;

a first actuator to move the display sled between a test position and a load position, wherein the display sled to receive the DUT while the display sled is in the load position, wherein the DUT electrically couples to contacts of a contact region disposed on the display sled;

a lamp source supported by the frame and positioned to illuminate the DUT when the display sled is in the test position;

a measurement camera supported by the frame and positioned to capture one or more test images output by the DUT when the DUT is illuminated by the lamp source; driver circuitry to generate the one or more test images to drive the DUT, wherein the first actuator to move the display sled between the test position and the load position includes the first actuator to translate the display sled along a first axis, wherein movement of the display sled along the first axis moves both the DUT and the contact region relative to the lamp source, the measurement camera and the driver circuitry, and moves the DUT into optical alignment with the measurement camera and with the lamp source when the display sled is in the test position;

an electrical interconnect to temporarily establish an electrical connection between the driver circuitry and the DUT via the contacts of the contact region when the display sled is in the test position; and

a second actuator coupled to physically manipulate the electrical interconnect to engage or disengage the electrical connection between the driver circuitry and the DUT.

2. The apparatus of claim 1, further comprising:

a controller including operational logic and memory, wherein the controller is coupled to automate operation of at least the driver circuitry, the measurement camera, and the second actuator to acquire the one or more test images output from the DUT and to store test results in the memory indicative of an operational performance of the DUT.

3. The apparatus of claim 2, further comprising:

an identification camera positioned to capture a code image of a code disposed on the DUT, wherein the controller is coupled to store an identifier generated based on the code image indexed to the test results in the memory.

4. The apparatus of claim 3, wherein the controller includes logic that enables the lamp source when the DUT is determined, based upon the code image, to be one of a transmissive or reflective display and wherein the controller includes logic

that disables the lamp source when the DUT is determined, based upon the code image, to be an emissive display.

5. The apparatus of claim 3, wherein the identification camera and the measurement camera are supported by the frame above the display sled and the lamp source is supported by the frame below the display sled.

6. The apparatus of claim 3, wherein the measurement camera is supported by the frame below the display sled, the apparatus further comprising:

a polarizing beam splitter ("PBS") disposed below the display sled, wherein the PBS is positioned to pass light emitted from the lamp source as polarized light to the DUT and positioned to reflect the one or more test images output from the DUT to the measurement camera.

7. The apparatus of claim 1, wherein the lamp source comprises a light emitting diode ("LED") and a diffuser having an emission aperture aligned to illuminate the DUT when the display sled is in the test position.

8. The apparatus of claim 1, wherein movement of the display sled along the first axis further aligns the contacts of the contact region with terminals of the electrical interconnect when the display sled is in the test position, wherein the second actuator translates the terminals of the electrical interconnect relative to the contacts of the contact region in response to movement of the display sled into the test position.

9. The apparatus of claim 8, wherein the second actuator translates the terminals along a second axis that is orthogonal to the first axis.

10. The apparatus of claim 2, further comprising:

a tray for holding a plurality of DUTs in a pattern, wherein the tray is mountable to the display sled, wherein the first actuator includes a sled actuator coupled to the display sled to translate the display sled along two orthogonal directions, wherein the controller include logic to successively drive each of the plurality of DUTs with the one or more test images and to store a plurality of sets of test results in the memory to automate batch testing of the plurality of DUTs.

11. The apparatus of claim 2, wherein the measurement camera has sufficient resolution to identify a failure of a single pixel in the DUT.

12. The apparatus of claim 2, wherein the measurement camera is mounted with a translation adjustment to adjust an offset between the measurement camera and the DUT and the measurement camera includes a telecentric lens.

13. An automated method for testing one or more displays, the method comprising:

moving a display sled of a test instrument from a load position to a test position after a display under test ("DUT") has been inserted into a mount on the display sled, wherein the DUT, while in the mount, is electrically coupled to contacts of a contact region disposed on the display sled, wherein moving the display sled from the load position to the test position includes translating the display sled along a first axis, wherein translating the display sled along the first axis moves both the DUT and the contact region relative to a lamp source, a measurement camera and driver circuitry of the test instrument, and moves the DUT into optical alignment with the measurement camera and with the lamp source when the display sled is in the test position;

determining if the DUT requires external illumination for operation, and if so, illuminating the DUT with the lamp source when the sled is in the test position;

9

after the display sled moves to the test position, establishing, via the contacts, an electrical connection between the DUT and the driver circuitry;

with the driver circuitry, driving the DUT to emit one or more test images;

capturing the one or more test images emitted from the DUT with the measurement camera; and

analyzing the test images captured by the measurement camera of the test instrument with a controller to determine whether the DUT has one or more faults.

14. The automated method of claim **13**, further comprising: acquiring a code image of a code disposed on the DUT with an identification camera of the test instrument.

15. The automated method of claim **14**, wherein the determining if the DUT requires external illumination for operation is determined based upon the code image acquired with the identification camera.

16. The automated method of claim **15**, wherein the identification camera and the measurement camera are supported by a frame of the test instrument above the display sled and the lamp source is supported by the frame below the display sled.

17. The automated method of claim **15**, wherein the measurement camera is supported by a frame of the test instrument below the display sled, the automated method further comprising:

polarizing light emitted from the lamp source with a polarizing beam splitter disposed between the lamp source and the display sled to emit polarized light; and

10

reflecting the one or more test images output from the DUT towards the measurement camera, wherein the DUT comprises a reflective display.

18. The automated method of claim **13**, wherein the lamp source comprises a light emitting diode (“LED”) and a diffuser having an emission aperture aligned to illuminate the DUT when the display sled is in the test position.

19. The automated method of claim **13**, wherein translating the display sled along the first axis aligns the contacts of the contact region with terminals of an electrical interconnect of the test instrument when the display sled is in the test position, wherein establishing the electrical connection between the DUT and the driver circuitry comprises translating the terminals relative to the contacts in response to movement of the display sled into the test position.

20. The automated method of claim **13**, further comprising: moving the display sled from the load position to the test position after a plurality of DUTs in a tray have been mounted on the display sled; successively moving the tray to align each of the plurality of DUTs with the measurement camera; capturing one or more test images from each of the plurality of DUTs; and determining whether any of the plurality of DUTs are faulty based upon the one or more test images captured for each of the plurality of DUTs.

* * * * *